

Harness the combined powers of SEM and XPS

A dynamic workflow for a more comprehensive understanding of your samples

What is the CISA Workflow?

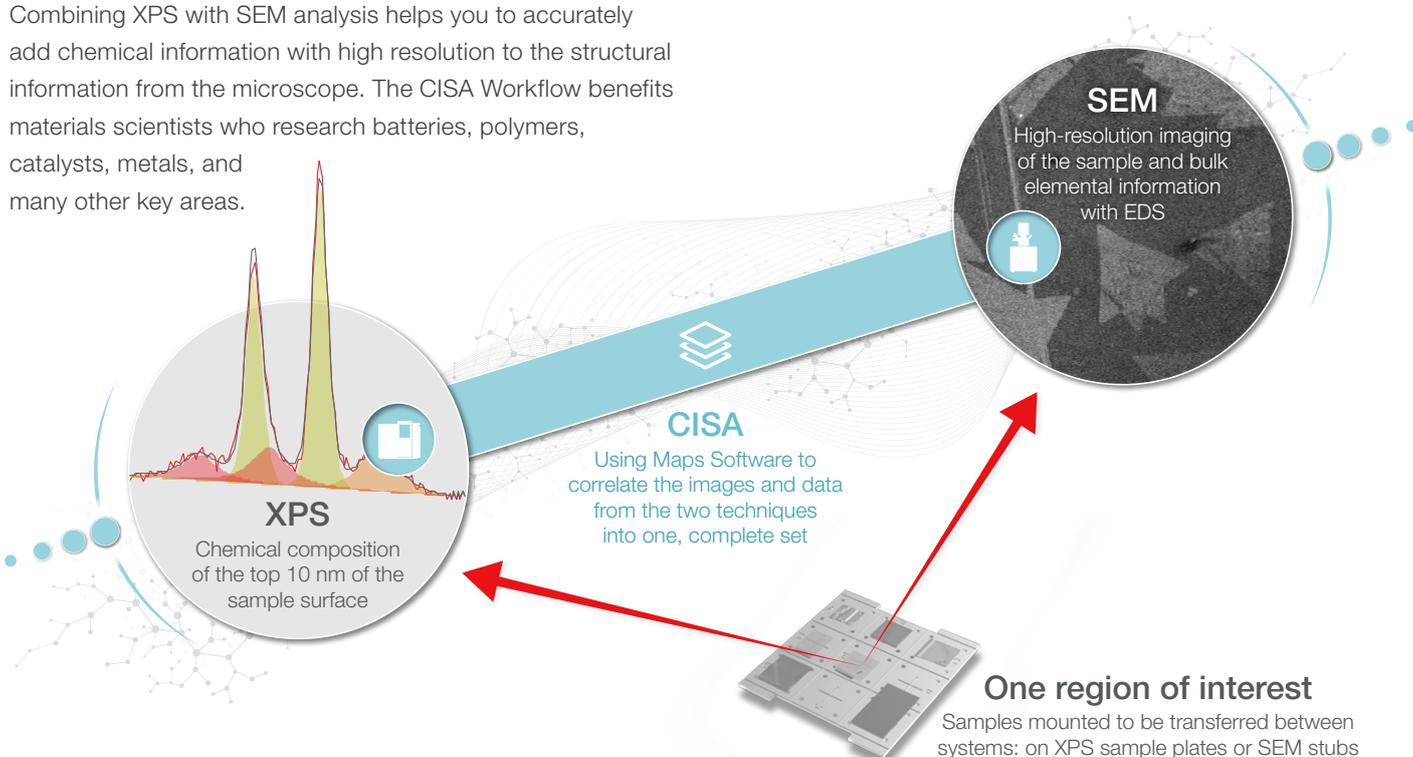
While it is important to get information from various sources, it can be difficult to collect all the data efficiently. With the new Thermo Scientific™ CISA (Correlative Imaging and Surface Analysis) Workflow, it is easy to bring together surface analysis and electron microscopy from the same points on the sample to build a better understanding.

Benefits of SEM + XPS

When you join the powers of SEM and XPS you will have more robust data to analyze, which helps you solve problems faster. Combining XPS with SEM analysis helps you to accurately add chemical information with high resolution to the structural information from the microscope. The CISA Workflow benefits materials scientists who research batteries, polymers, catalysts, metals, and many other key areas.

Confidence from correlation

The integration of Thermo Scientific Maps™ Software into the CISA Workflow enables you to easily target the exact point of interest after sample transferal between systems, providing better data correlation between XPS and SEM tools for more comprehensive surface analysis. The CISA Workflow allows you to visualize the surface of the sample, and understand the chemical composition, confident that the data has come from the same place.



Learn more at thermofisher.com/cisa

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